Search Notes



Applicant(s)/Patent Unde Reexamination

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10786164 BEAN ET AL.

Examiner Art Unit

 SEARCHED

 Class
 Subclass
 Date
 Examiner

 182
 18
 4/27/07
 acs

 update
 10/10/07
 acs

 update
 7/9/08
 acs

Chin-Shue, Alvin C

SEARCH NOTES				
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U.S. Patent and Trademark Office Part of Paper No.: 20080710